

WBG-Based High Output Power Electronics

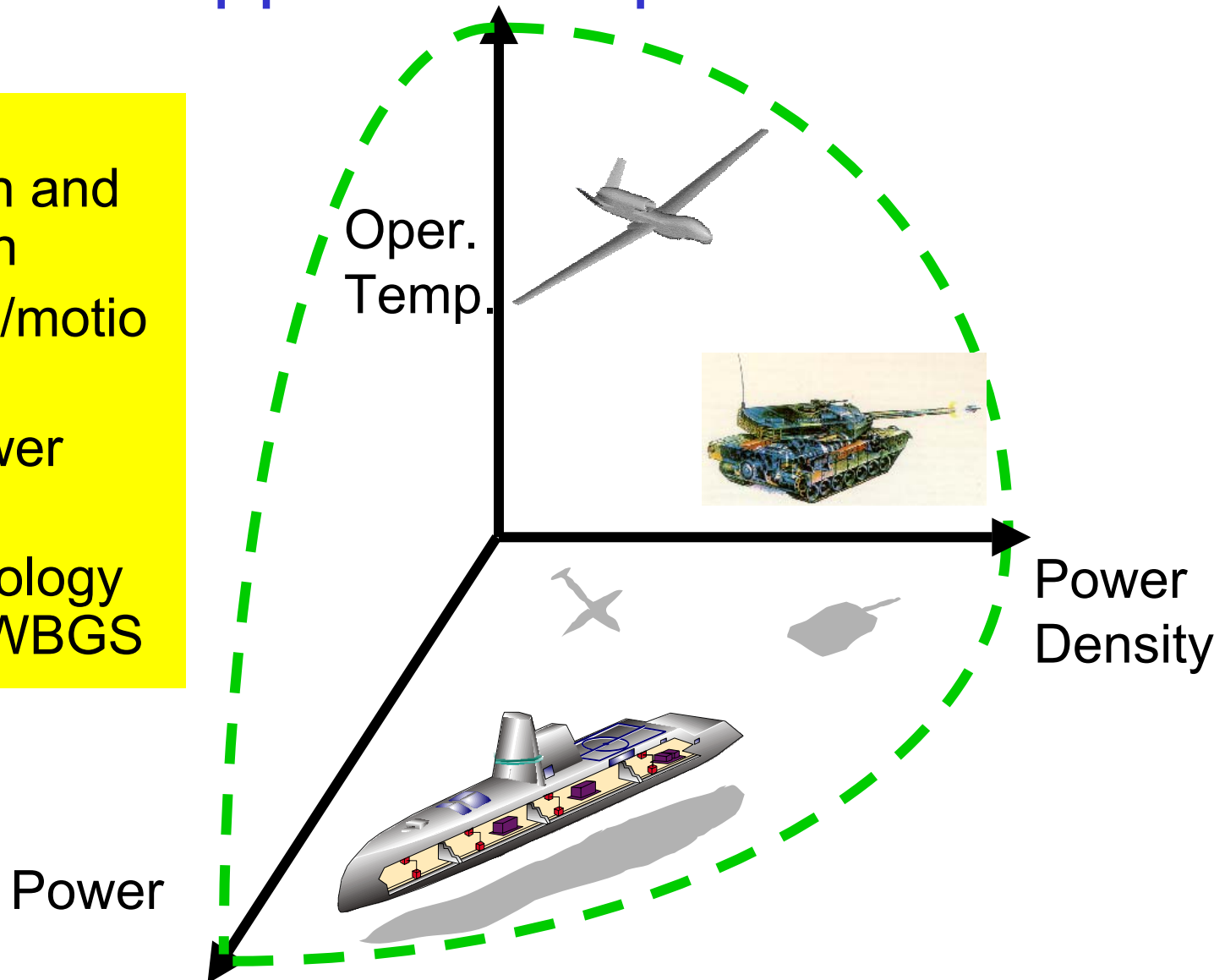
Daniel J. Radack
Institute for Defense Analyses

Outline

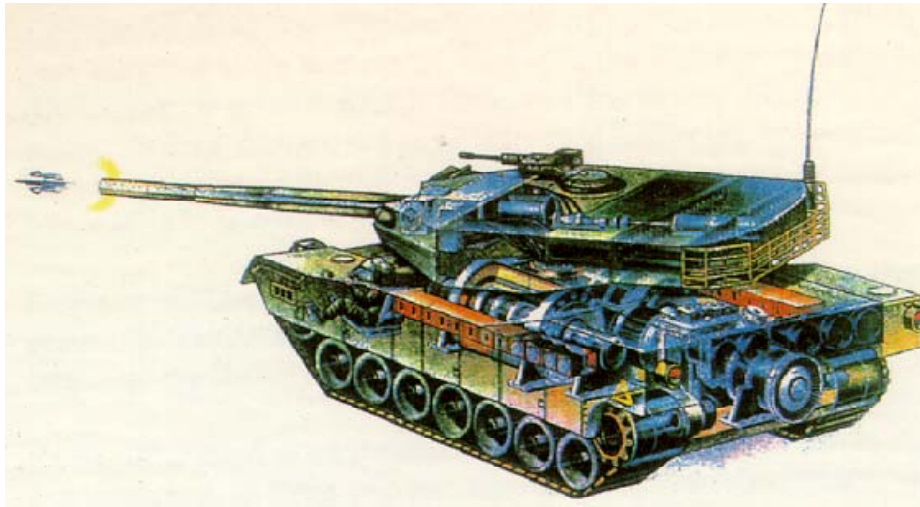
- Applications/needs for high output power electronics
- High Power Solid-State Electronics Program Goals and Accomplishments
 - FY97 – FY00
 - Managed by E.R. Brown then D.J. Radack
- WBG Technology Opportunities for advanced power applications

High Output Power Electronics Application Space

- Power Distribution and Conversion
- Propulsion/motion control
- Pulse Power Switching
- One technology solution - WBGS



Electric Combat Vehicle



Needs to be light!

Active armor

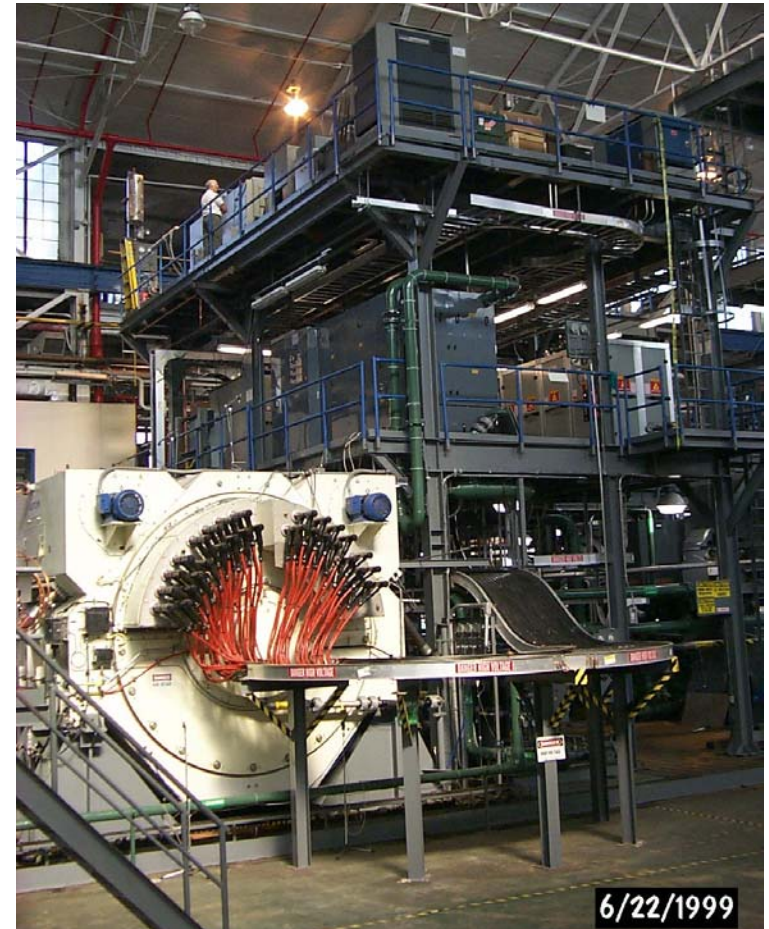
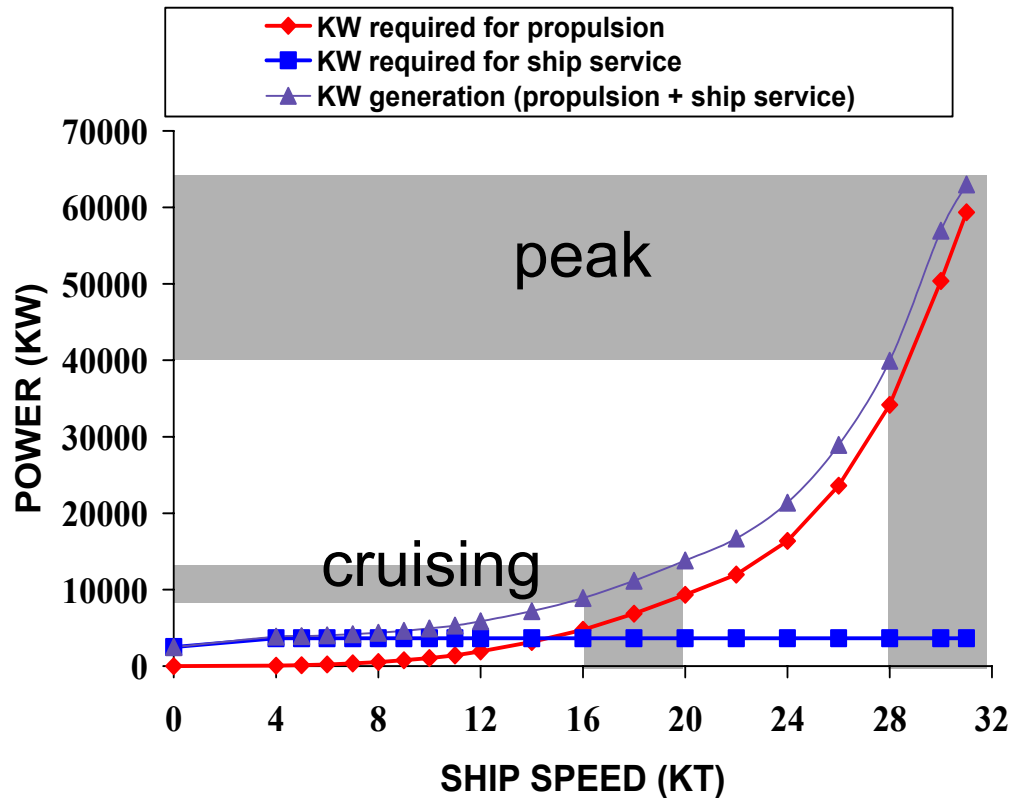
Active suspension

EM Weapons

Energy efficiency

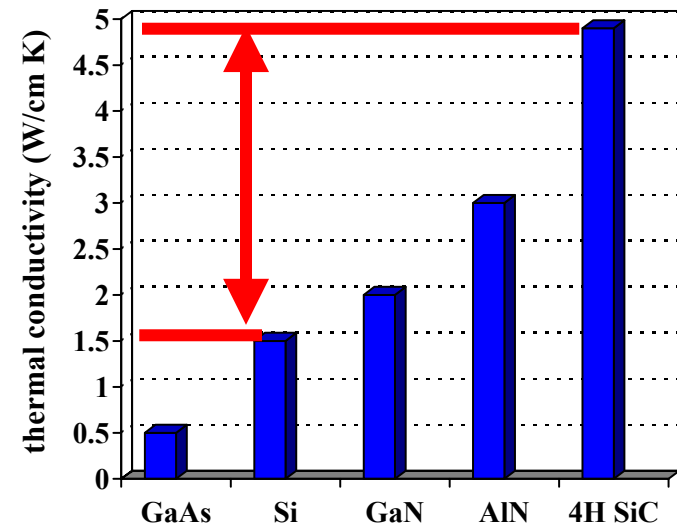
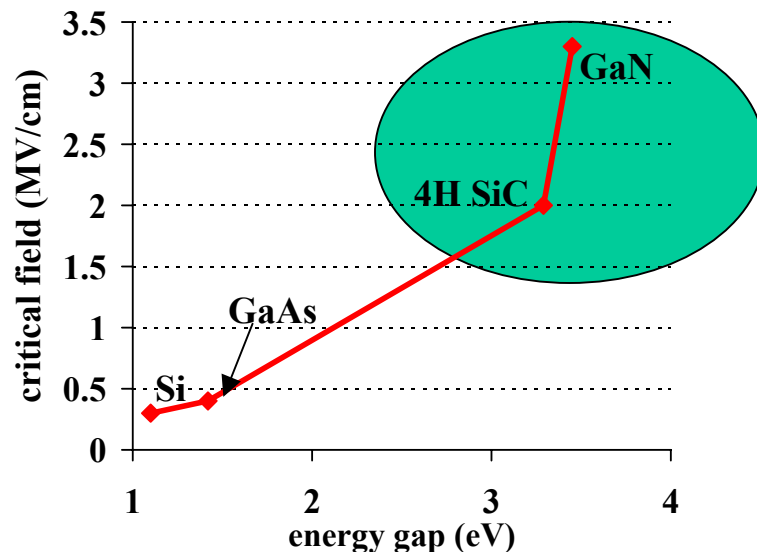
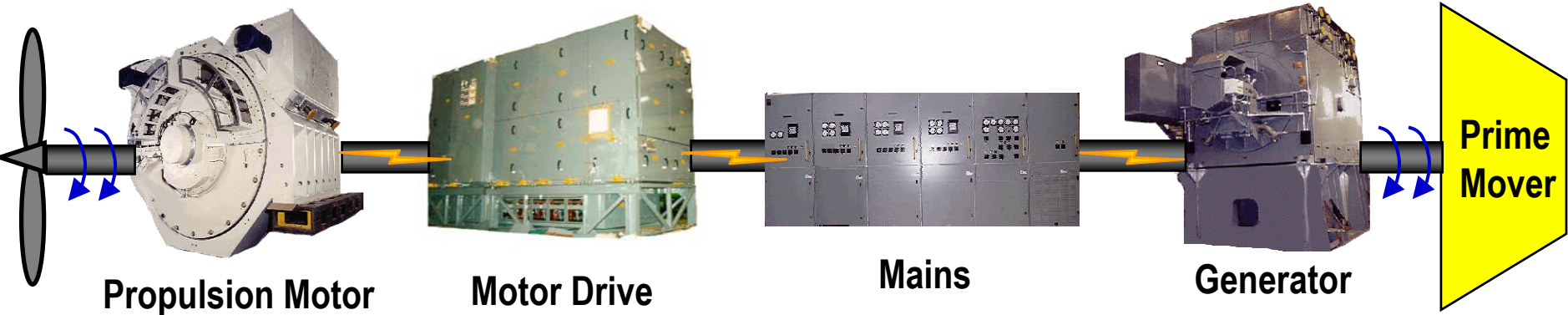
- Traction motor controller: $>300\text{kW}$, $>2\text{kV}$, $>750\text{A rms}$, $>25\text{kHz}$, 150°C
- EM weapons: $>200\text{kJ}$ energy, 40kV , $di/dt > 10\text{kA/us}$, 100kHz , low losses
- HP Inverter: 10MW for $0.1\text{-}0.5\text{s}$, 10kV , 3kA , 25kHz , compact size

Ship Power Application



Motor Controller is key – SiC will increase performance and efficiency with smaller size

Power Electronics for Motors

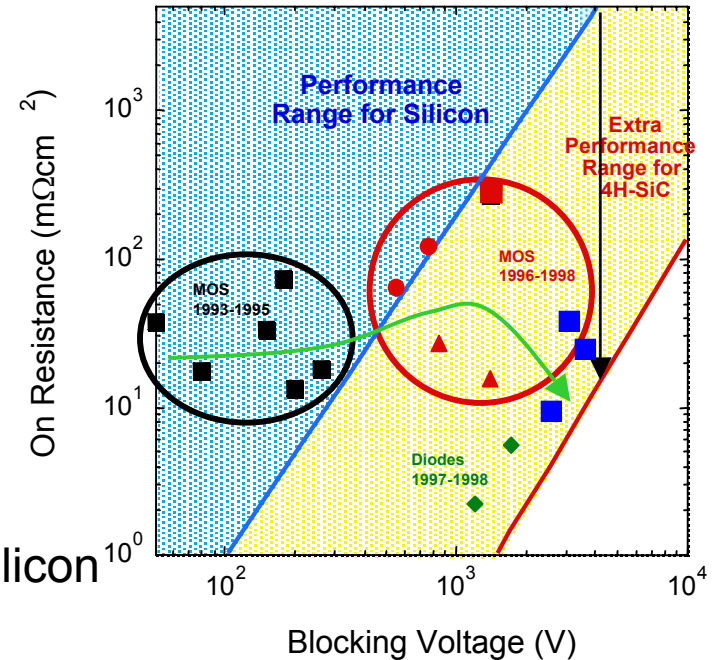
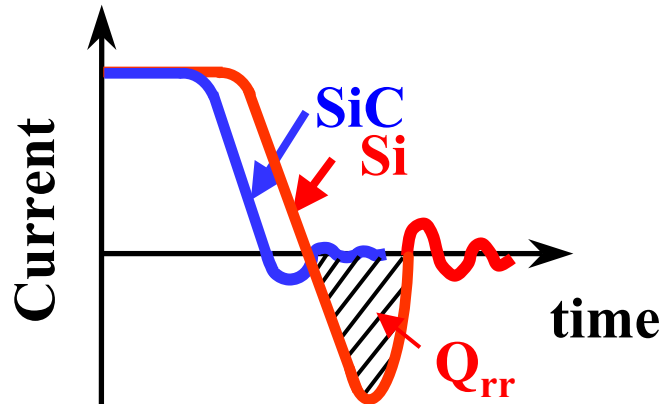


Motor performance depends on drive electronics – SiC power devices will enable high performance motor drives

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- Applications/needs for high output power electronics
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Silicon Carbide Power Electronics



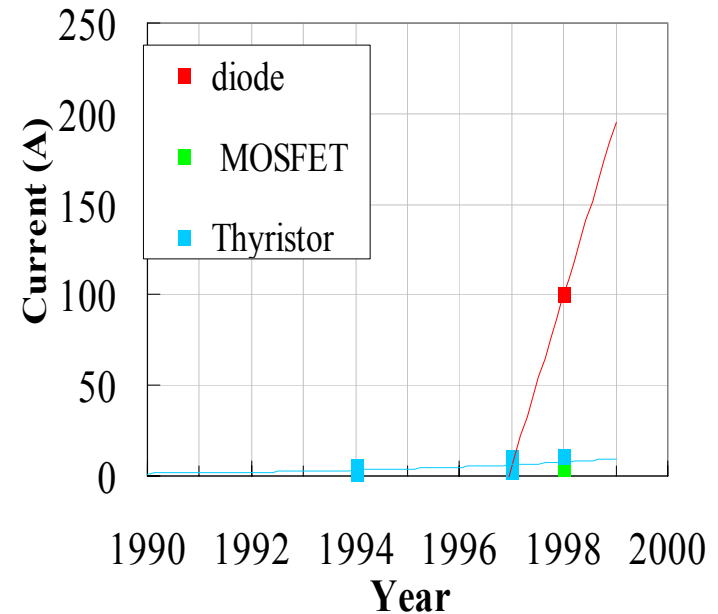
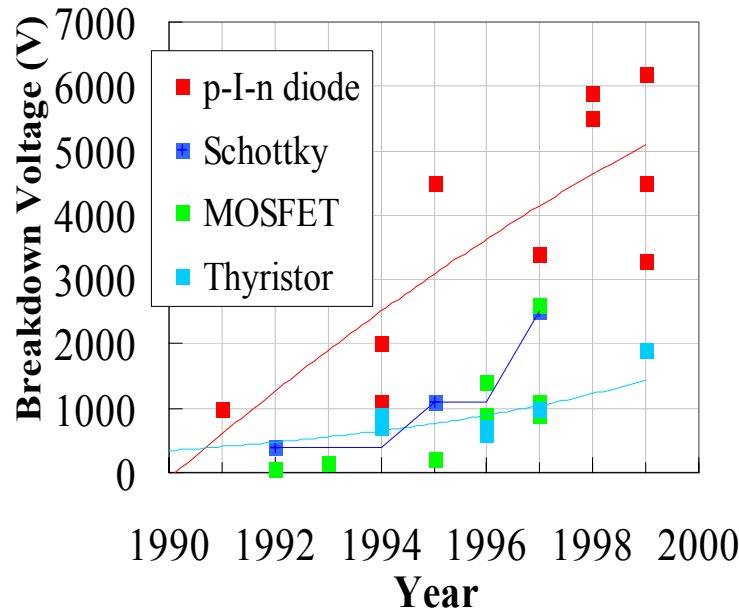
- (1) ~8X higher breakdown electric field than Silicon
- (2) 3X higher thermal conductivity and larger band gap energy than Si
- (3) 10X faster switching speed over Si, near zero reverse recovery
- (4) 10-50X reduction in complete HV circuit

Silicon Carbide material properties a match for high power electronics – bulk electronic materials now available!

High Power Solid-State Program Accomplishments

- Program Duration: FY97-00, \$30M (\$12M cost share from EPRI)
 - Industry, academia, gov't participation in program
 - Project summaries and program participant final briefings are on MTO web site in the “High Power Solid-State Electronics” Archives
 - TTO CHPS App., DSO SiC materials and AF Title 3
- Developed and transferred high yield unit process technologies for SiC power devices (diodes and thyristors)
 - epitaxial layer growth, doping, contacts, oxides
- Demonstrated feasibility of fabricating SiC high power electronic devices in industrial fabrication lines (diodes, FETs, thyristors)
- Demonstrated assembly and packaging technology for 1kW/cm² SiC power devices first ever all SiC electronic assemblies
 - Fabricated die for TTO CHPS

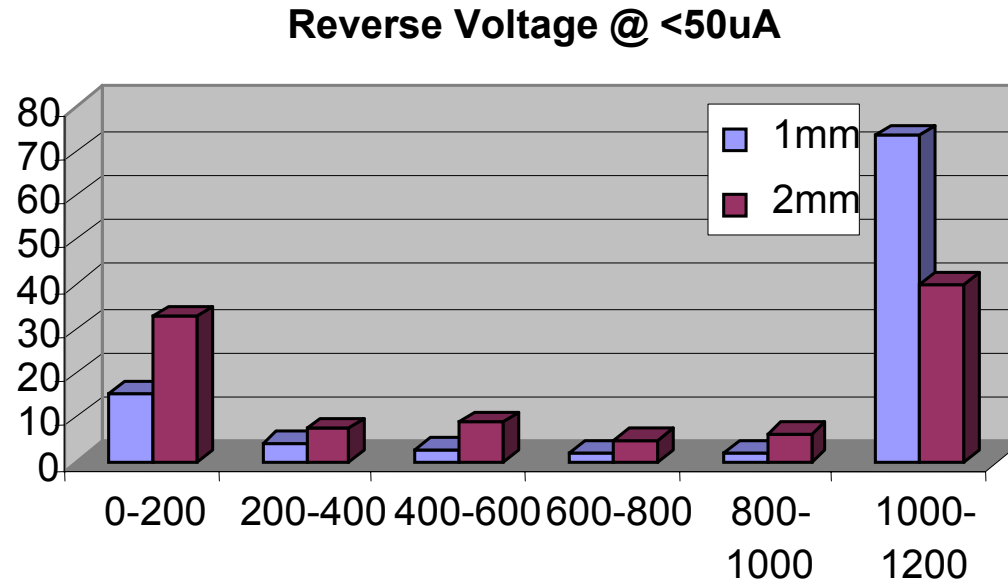
Progress in SiC Power Electronics



Selected SiC Device Accomplishments (FY00):

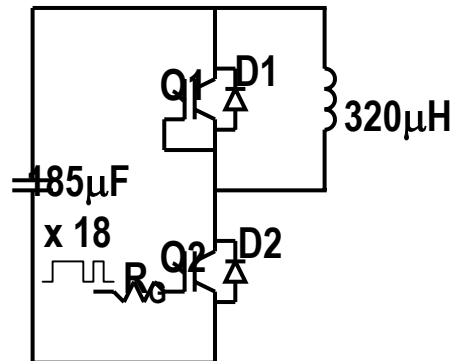
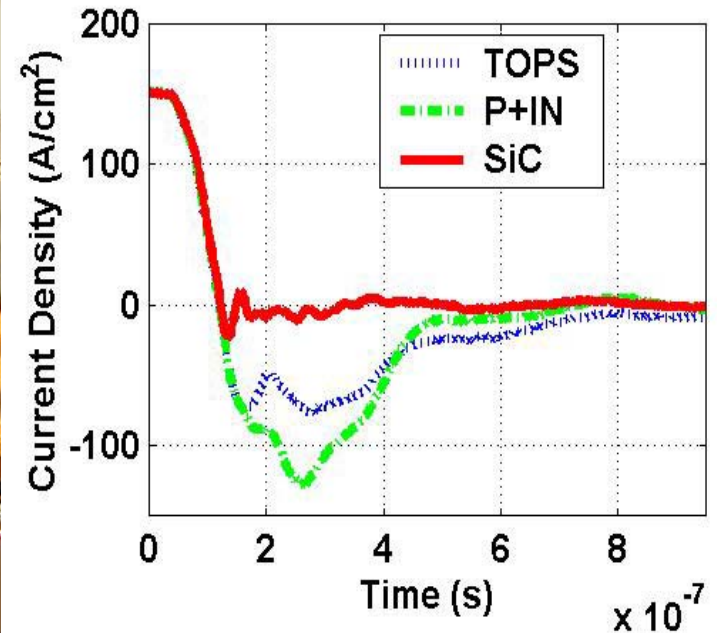
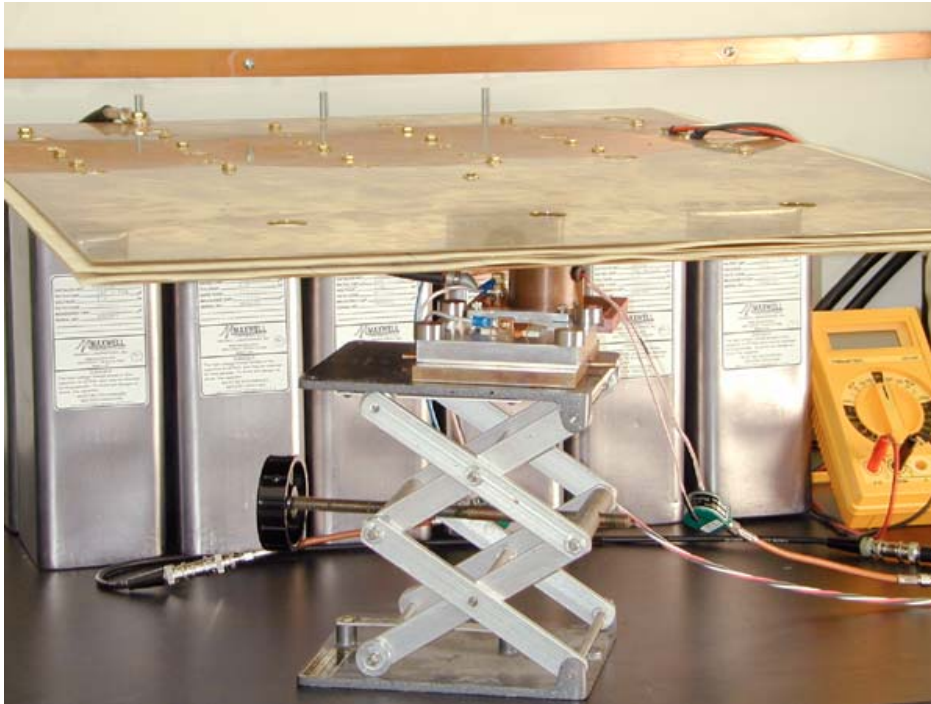
- 6 kV diodes
- Yielded hundreds of >5kV diodes
- >100 A diode assembly
- 3 kV GTOs
- 69 A conduction / 11 A turn-off GTOs

HP Diodes Show >70% Yield



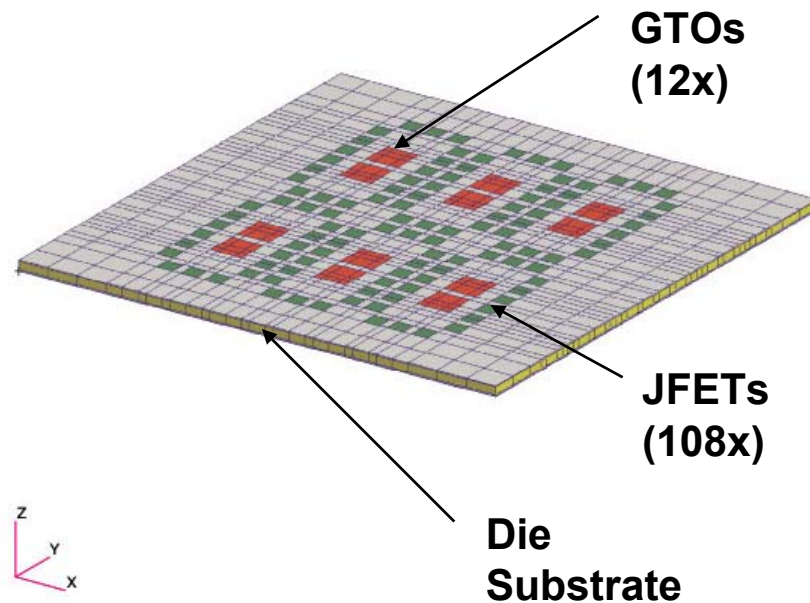
- Strong dependence on epi quality
- Reasonable (40%) yields even at 2 mm

High Power Testing



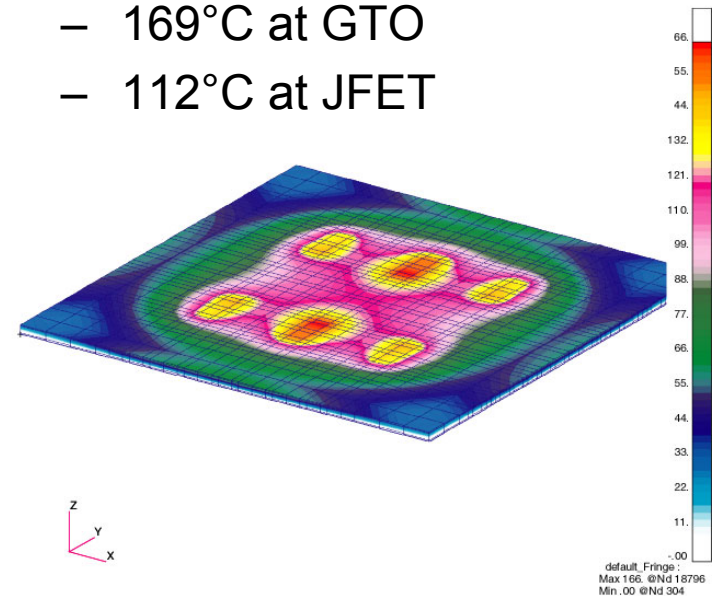
Minimal Diode Reverse Recovery Charge!!!

Electrothermal Modeling



Circumferential Cooling

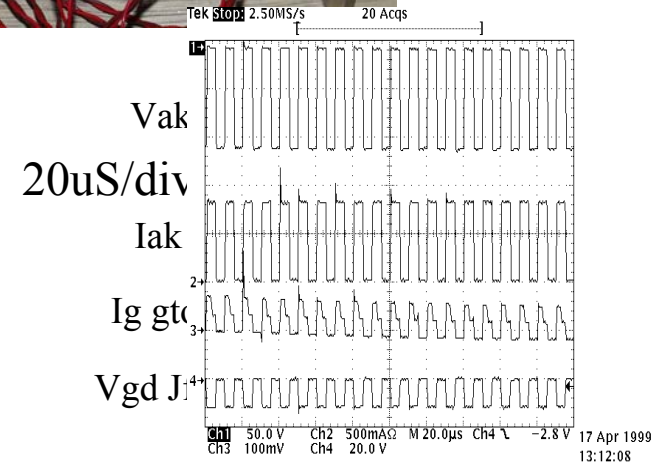
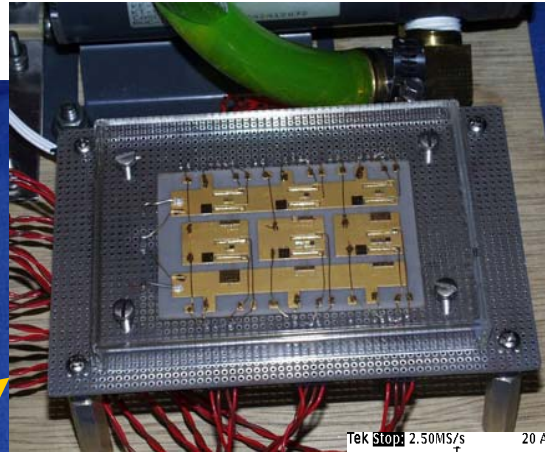
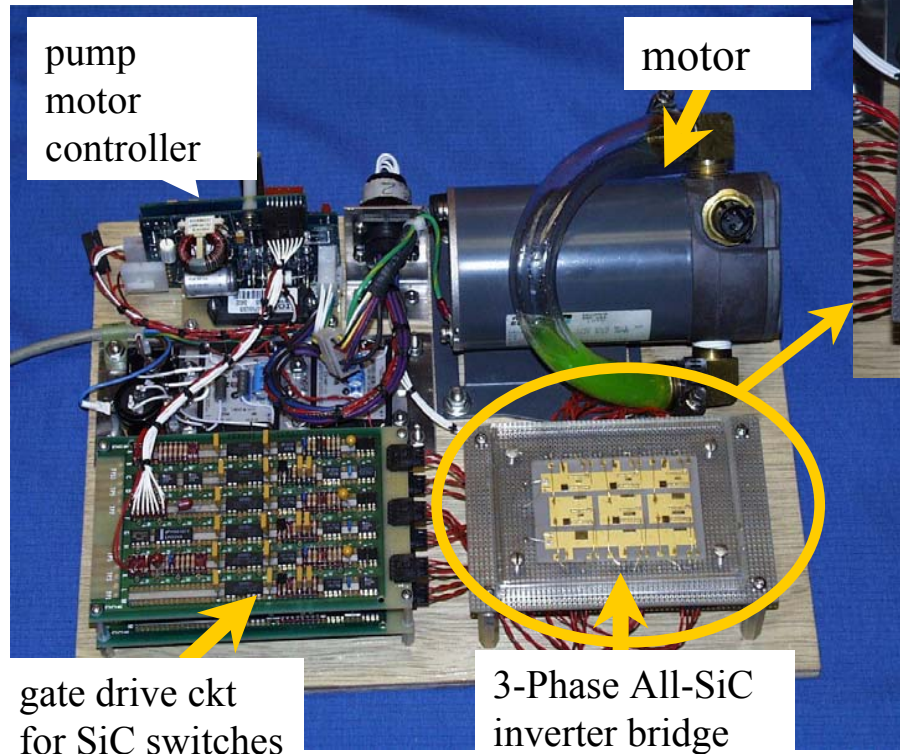
- Circum cooling with CuW Encapsulated pyrolytic graphite
- Maximum Temperature
 - 169°C at GTO
 - 112°C at JFET



Completed Coupled Electrothermal Models for SiC Devices, Excellent Agreement to Experimental Data

First Operational All SiC Motor Drive

1kW, 3-phase PWM motor drive controller



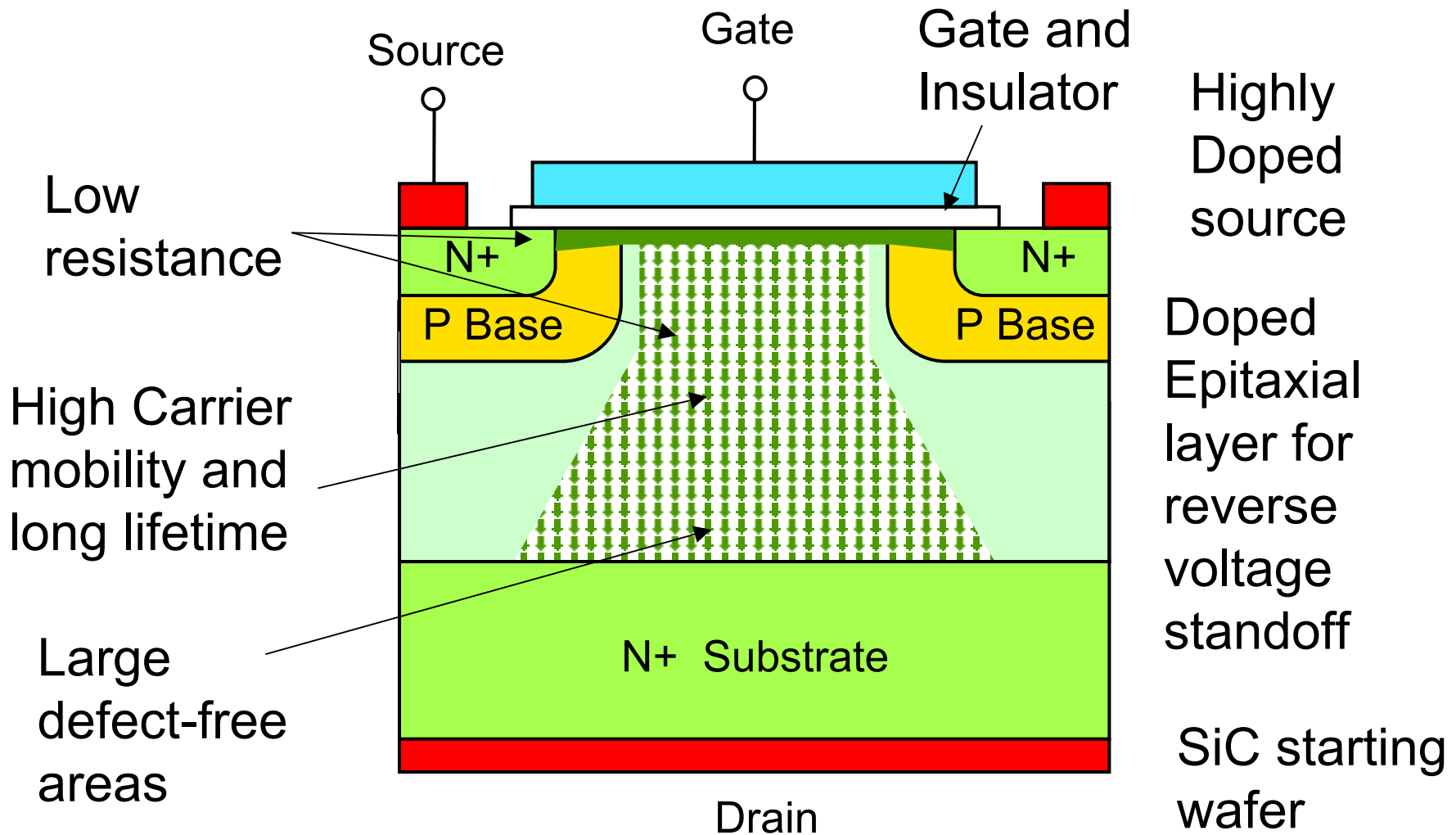
SiC Microinverter operating at 100kHz, 100V, 0.75 amp confirms SiC promise and models

MTO SiC Devices Used For First Ever Demo of all-SiC Power Electronics Circuit

Outline

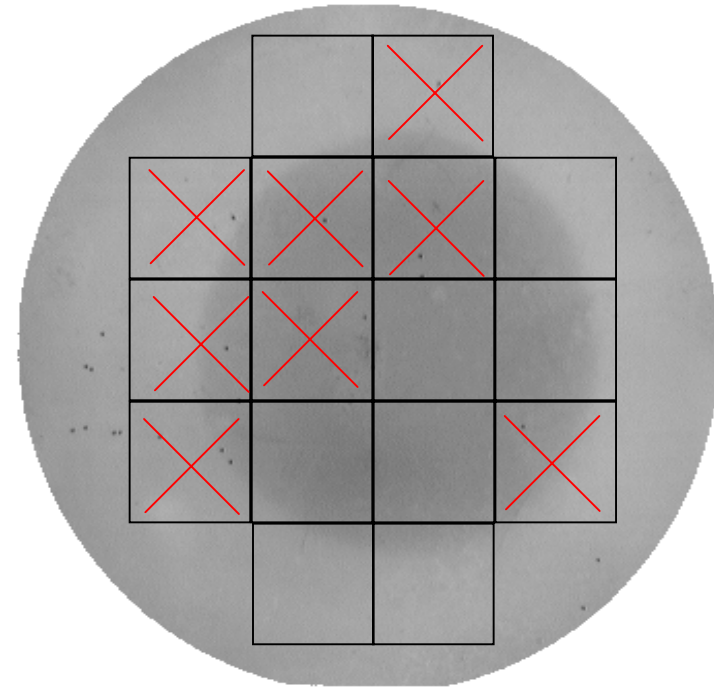
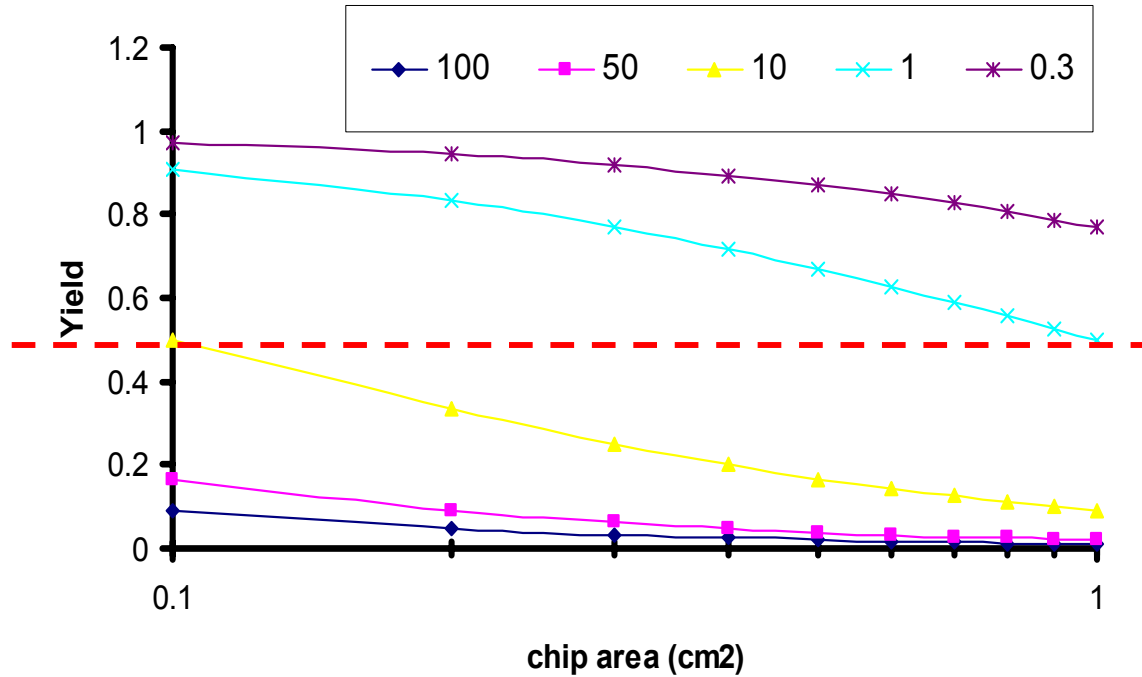
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 - Increase chip area
 - MOS structures

SiC Electronic Materials for Power



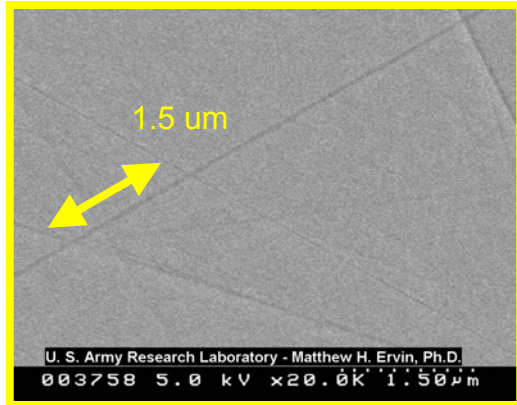
4H SiC is best overall choice for high voltage and current

New Direction: Increase Usable Chip Area for High Power Devices



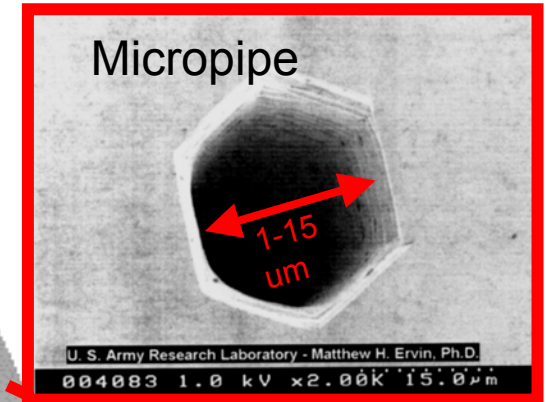
Defect free Cm² area chips necessary for yielding high current, high voltage devices

Material Issues for High Power



Surface
Defects:

- Eliminate
- Mitigate



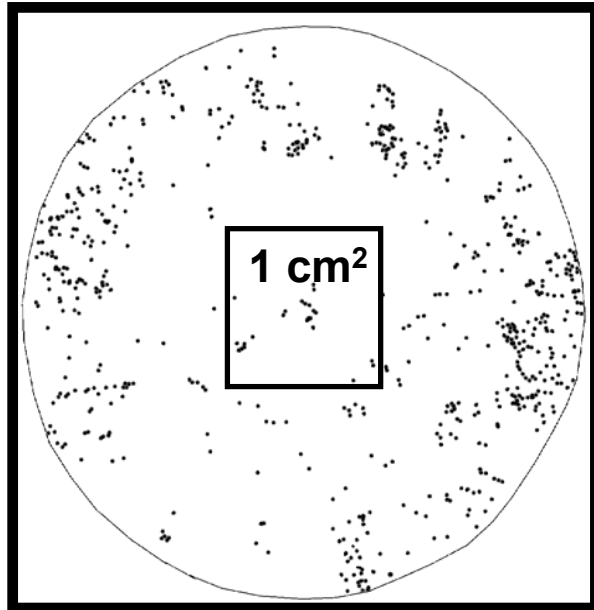
Wafer
Defects:

- Eliminate
- Cover
- Fill

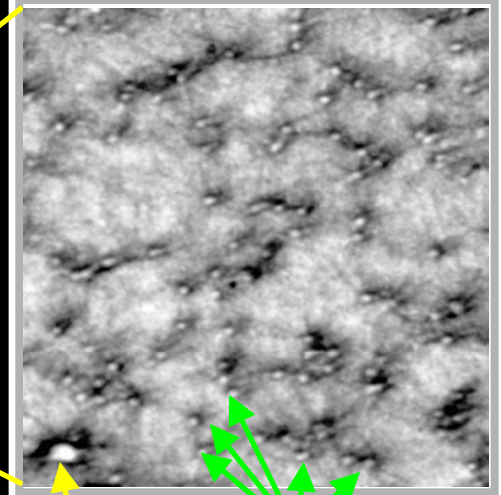
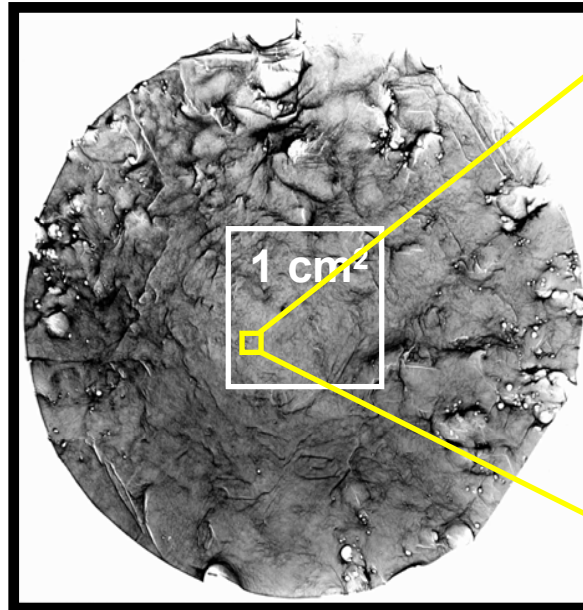
Challenges: Large Defect Free Areas (cm^2) for HP Devices

SiC Wafer Defects

Micropipe Map



X-Ray Topograph



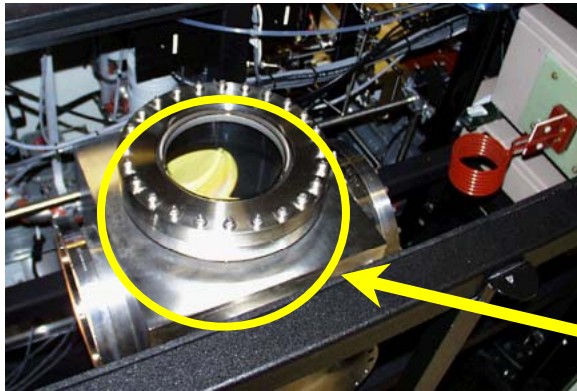
Micropipe

Elementary
Screw
Dislocations

Total Defect Density >> Micropipe Density

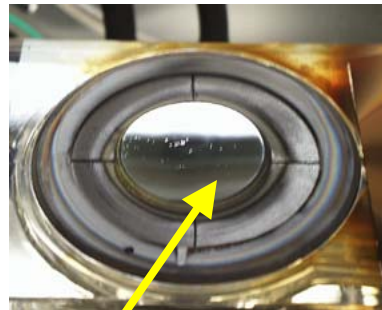
High Temperature SiC CVD for WBG Epi

Need ~ **500 μm** (@ $1 \times 10^{14} \text{ cm}^{-3}$) Epi Layer for 25 kV blocking voltage.



Current Epi Growth Rate Limitations:
CVD Temp up to 1600°C
growth rates $\sim 3.5 \mu\text{m/h}$
500 μm in >140 hours!

High Temperature Epi:
Temp up to 2250°C
growth rates $\sim 100 \mu\text{m/h}$
500 μm in ~ 5 hours or less !
Halide-assisted, low T growth



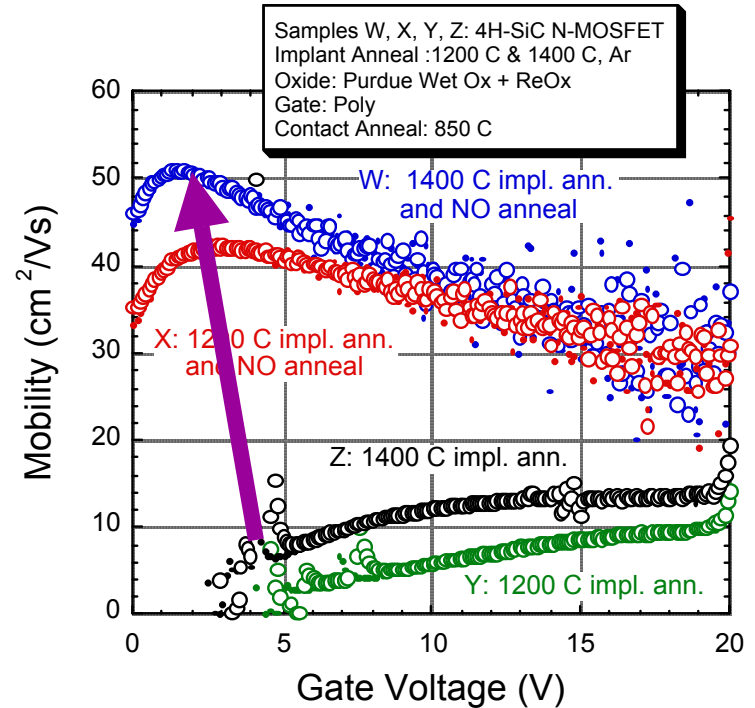
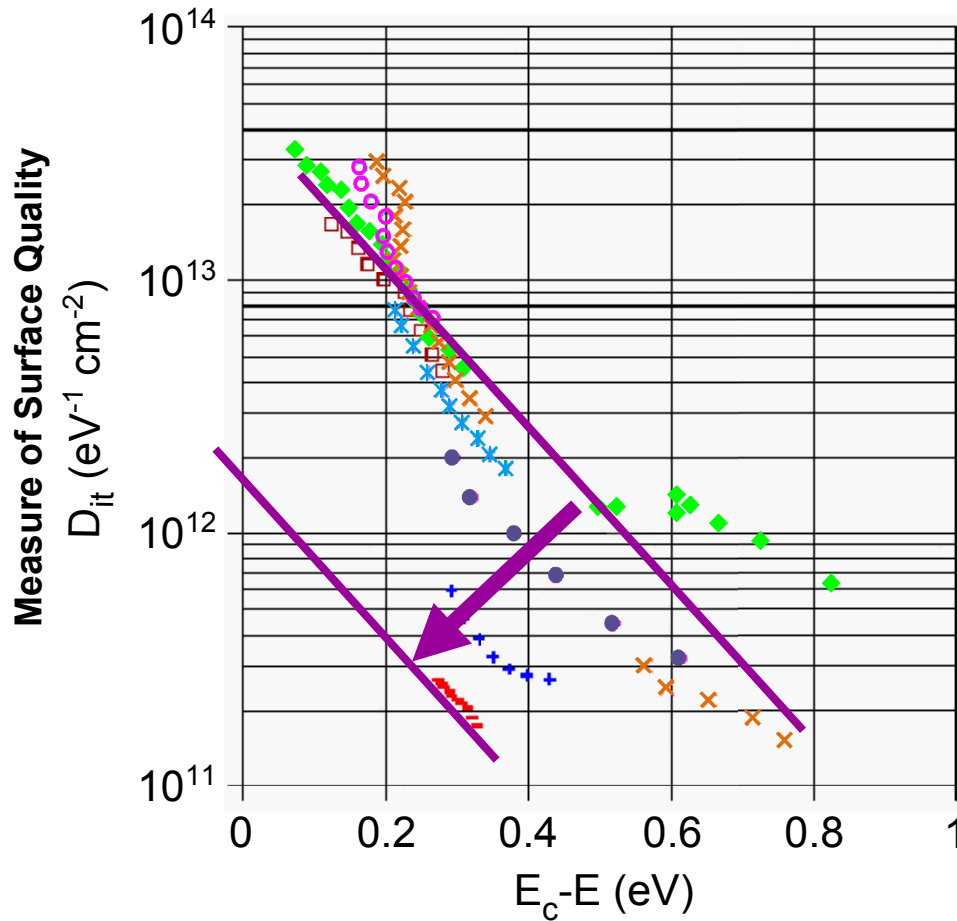
SiC Epi

Technical Challenges:

- Component Degradation
- Impurity/Dopant Control
- Morphology & Defects
- Pre-cracking of Precursors

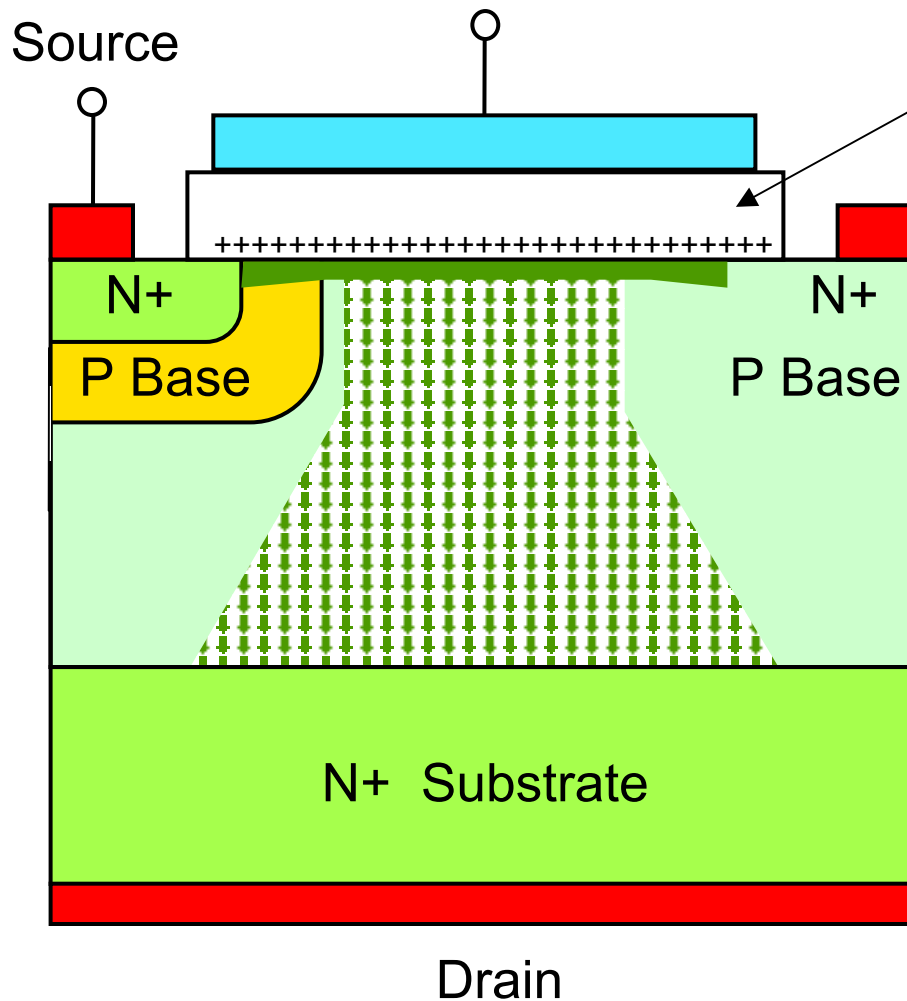
High Temperature Epi Needed for High Growth Rate of WBG

Oxy-Nitride Process Breakthrough for SiC Oxides



Oxy-Nitride Process Proven To Reduce Surface States and Increase Channel Mobility up to 5X to 90 $\text{cm}^2/\text{V-s}$

Ferroelectric Gate Insulators



Lithium Niobate, Lithium Tantalate, Li Gallate have promising properties:

100-1000X inversion charge density

Low field in dielectric

Normally Off

Positive temp. coeff.

Challenges:

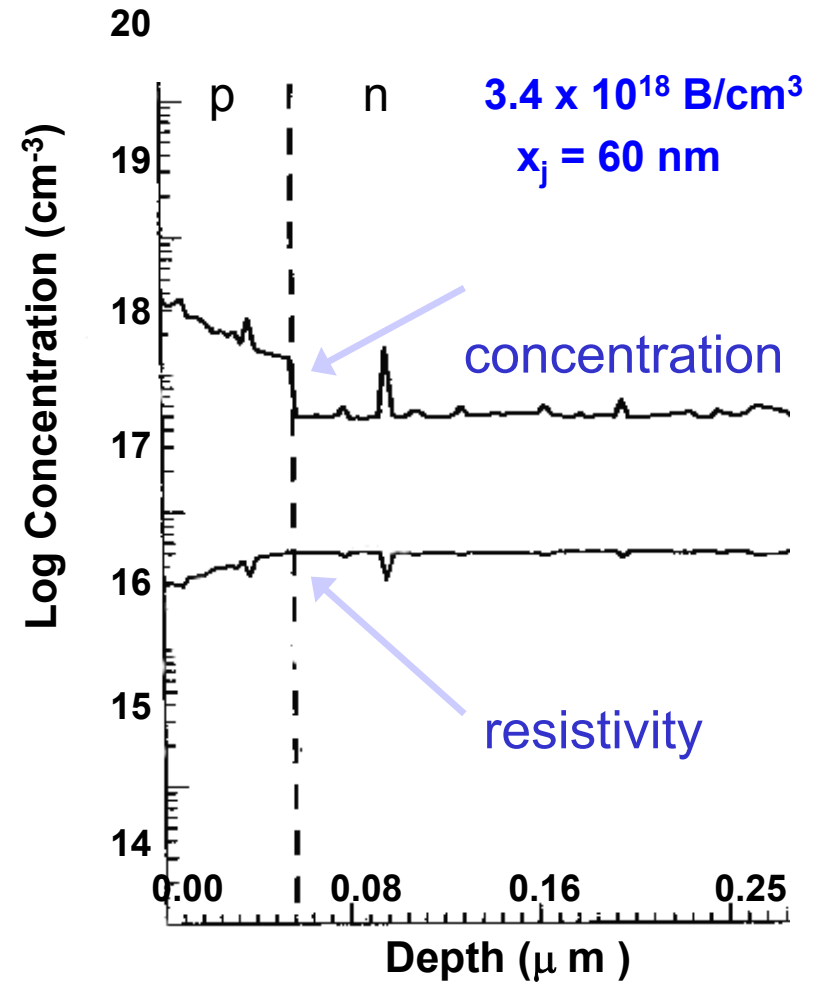
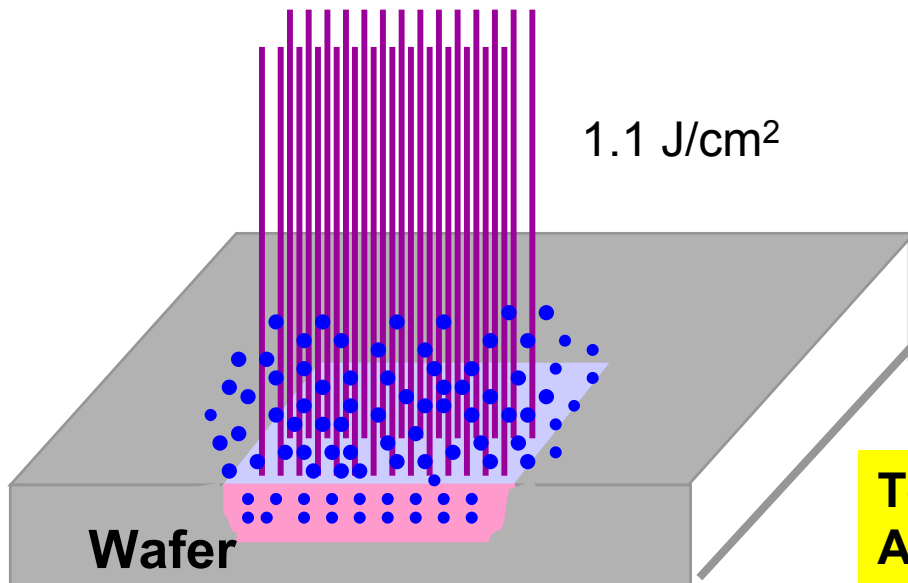
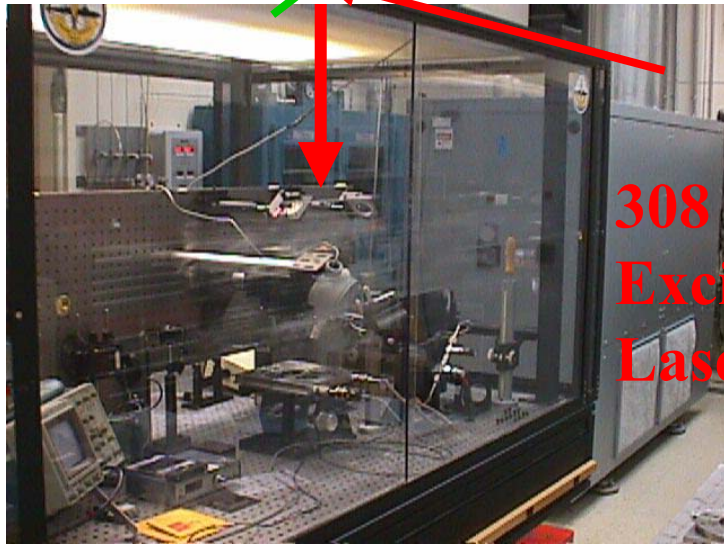
- Growth/deposition with low interface states for high V
- Temp. stability
- Breakdown field

High Voltage Ferroelectrics Can Eliminate Thermal Oxides

Gas Immersion Laser Doping

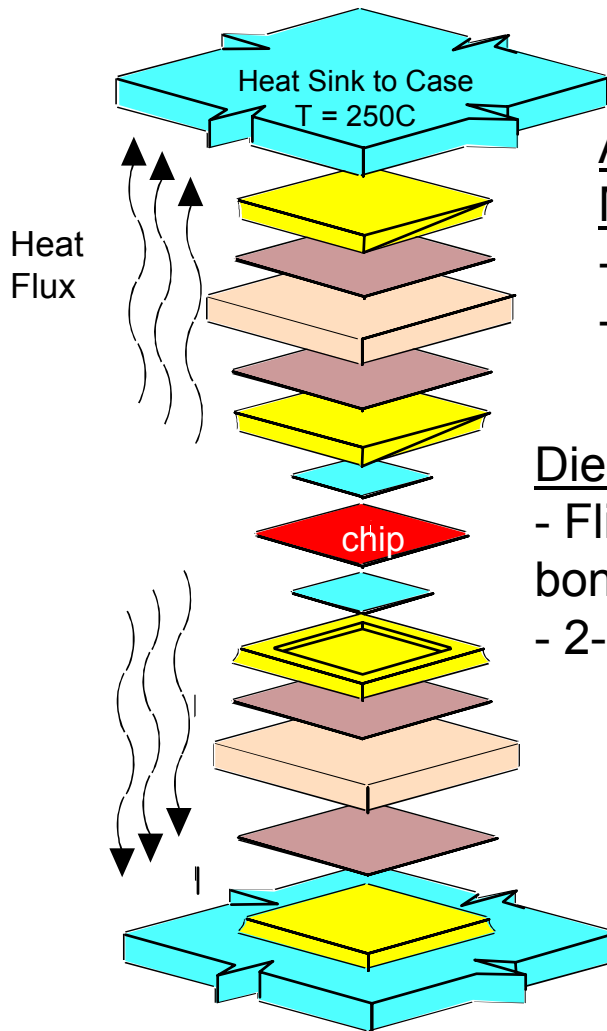
Doping Results

1 pulse
 $\Phi =$



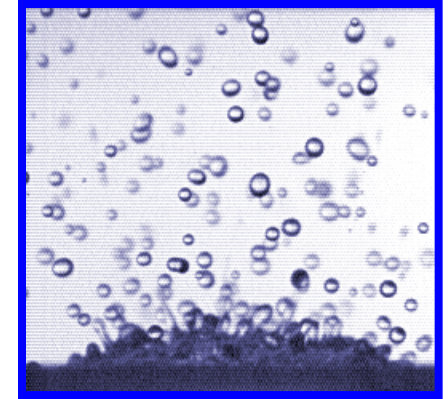
Technology Proven with Silicon FETs –
Achieving doping above solid-state
diffusion limit using laser processing

Integration for WBG Electronics



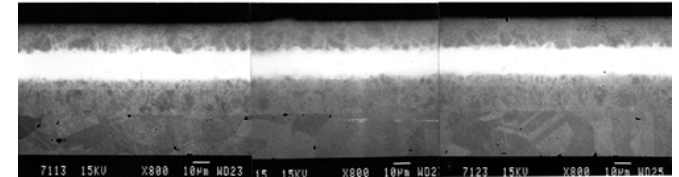
AC and Transient Thermal Management

- Phase change materials
- Integrated spray cooling



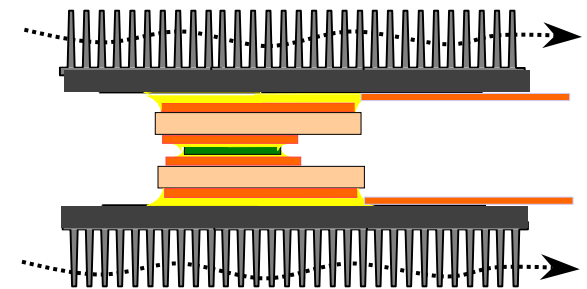
Die Attach

- Flip chip via Cu/Sn alloy bonding
- 2-sided cooling



Substrates

- High voltage insulators
- High thermal conductivity
- Low TCE mismatch



Integration and Thermal Management Is Critical for Realizing WBG Device and Circuit Benefits at System Level

Technology Opportunities for R&D in WBG Power Electronics

- Materials and Processes
 - Defect reduction and mitigation
 - Large areas for high current, high voltage
 - Oxides, epi layers, doping activation, mobility, etc.
- Devices
 - MW and beyond switches
 - Novel triggering and commutation
 - Defeat realtime defect growth and propagation issues (minority carrier injection effects)
 - Integrated Structures and Thermal Management
- Applications
 - Compelling!